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APPLICATION NO. 10/059,171

APPLICANT TAKAO YONEHARA, et al.

FILING DATE January 31, 2002

GROUP 2871 2813

U.S. PATENT DOCUMENTS

EXAMINER INITIALS/NAME	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
TW	6,075,280	06/13/00	Yung et al.	257	620	
	6,136,668	10/24/00	Tamaki, et al.	438	462	
	6,186,384	02/13/01	Sawada	225	2	
	6,465,329	10/15/02	Glenn	438	462	
	2002/0076904	06/20/02	Imler	438	462	
TIU	2002/0100941	08/01/02	Yonehara, et al.	257	359	

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

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8/30/02

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FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO. 00862.022499.	APPLICATION NO. 10/059,171	
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			APPLICANT TAKAO YONEHARA, ET AL.		
			FILING DATE January 31, 2002	GROUP 2813	
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*EXAMINER INITIAL	DOCUMENT NUMBER	TRADEMARK DATE	NAME	CLASS	SUBCLASS
<i>TW</i>	6,455,398	09/24/02	Fonstad, Jr. et al.	438	459
	6,500,731	12/31/02	Nakagawa, et al.	438	455
	6,602,761	08/05/03	Fukunaga	438	459
	6,677,183	01/13/04	Sakaguchi, et al.	438	113
<i>TW</i>	6,682,990	01/27/04	Iwane, et al.	438	458
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OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)					

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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>TW</i>		6,190,937	02/20/2001	Nauagawa, et al.	438	67	
		6,222,513	03/10/1998	Howard, et al.	345	84	
		6,258,698	07/10/2001	Iwasaki, et al.	438	455	
		6,306,729	10/23/2001	Sauaguchi, et al.	438	458	
		6,331,208	12/18/2001	Nishida, et al.	117	89	
		6,342,433	01/29/2002	Ohmi, et al.	438	455	
<i>TW</i>		6,382,292	05/07/2002	Ohmi, et al.	156	584	
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<i>TW</i>	EP	1 122 794	08/08/2001	Europe			
	EP	858 110	08/12/1998	Europe			
	EP	849 788	06/24/1998	Europe			
<i>TW</i>	JP	11-316397	11/16/1999	Japan	G02F		Abstract
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
<i>TW</i>		Shimoda, T., et al: "Surface Free Technology By Laser Annealing (SUFTLA)" International Electron Devices Meeting 1999. IEDM. Technical Digest. Washington, DC, Dec. 5-8, 1999, New York, NY: IEEE, US, Aug. 1, 1999 (1999-08-01), pages 289-292, XP000933199 ISBN: 0-7803-5411-7.					
EXAMINER	<i>Theresa</i>			DATE CONSIDERED	8/30/04		

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